

May 2001

# **FQPF11P06**

#### **60V P-Channel MOSFET**

## **General Description**

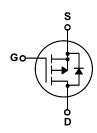
These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand a high energy pulse in the avalanche and commutation modes. These devices are well suited for low voltage applications such as automotive, DC/DC converters, and high efficiency switching for power management in portable and battery operated products.

#### **Features**

- -8.6A, -60V,  $R_{DS(on)}$  = 0.175 $\Omega$  @V<sub>GS</sub> = -10 V Low gate charge ( typical 13 nC)
- Low Crss (typical 45 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- 175°C maximum junction temperature rating





# Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter		FQPF11P06	Units
V <sub>DSS</sub>	Drain-Source Voltage		-60	V
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°	°C)	-8.6	Α
	- Continuous (T <sub>C</sub> = 100°C)		-6.08	Α
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	-34.4	Α
V <sub>GSS</sub>	Gate-Source Voltage		± 25	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	160	mJ
I <sub>AR</sub>	Avalanche Current	(Note 1)	-8.6	Α
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	3.0	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-7.0	V/ns
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25°C)		30	W
	- Derate above 25°C		0.2	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +175	°C
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

# **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		5.0	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	-60			V
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	$I_D$ = -250 μA, Referenced to 25°C		-0.07		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -60 V, V <sub>GS</sub> = 0 V			-1	μА
		V <sub>DS</sub> = -48 V, T <sub>C</sub> = 150°C			-10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = -25 V, V <sub>DS</sub> = 0 V			-100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	$V_{GS} = 25 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA
On Cha	racteristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-3.0		-5.0	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = -10 V, I <sub>D</sub> = -4.3 A		0.14	0.175	Ω
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = -30 \text{ V}, I_D = -4.3 \text{ A}$ (Note 4)		4.75		S
C <sub>iss</sub>	Input Capacitance Output Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0  MHz		420 195	550 250	pF pF
C <sub>rss</sub>	Reverse Transfer Capacitance			45	60	pF
Switchi	ing Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time	$V_{DD} = -30 \text{ V}, I_{D} = -5.7 \text{ A},$		6.5	25	ns
t <sub>r</sub>	Turn-On Rise Time	$R_G = 25 \Omega$		40	90	ns
t <sub>d(off)</sub>	Turn-Off Delay Time			15	40	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4, 5)		45	100	ns
$Q_g$	Total Gate Charge	$V_{DS} = -48 \text{ V}, I_{D} = -11.4 \text{ A},$		13	17	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = -10 V		2.0		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4, 5)		6.3		nC
Drain-S	Source Diode Characteristics a	nd Maximum Ratings				
I <sub>S</sub>	Maximum Continuous Drain-Source Diode Forward Current				-8.6	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode F	ode Forward Current			-34.4	Α
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = -8.6 A			-4.0	V
t <sub>rr</sub>	Reverse Recovery Time	V <sub>GS</sub> = 0 V, I <sub>S</sub> = -11.4 A,		83		ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		0.26		μС

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 2.5mH, I<sub>AS</sub> = -8.6A, V<sub>DD</sub> = -25V, R<sub>G</sub> = 25 Ω, Starting T<sub>J</sub> = 25°C 3. I<sub>SD</sub> ≤ -11.4A, di/dt ≤ 300A/μs, V<sub>DD</sub> ≤ BV<sub>DSS</sub>, Starting T<sub>J</sub> = 25°C 4. Pulse Test : Pulse width ≤ 300μs, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

# **Typical Characteristics**

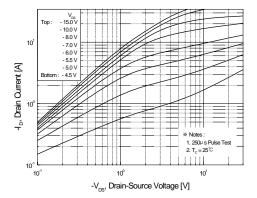


Figure 1. On-Region Characteristics

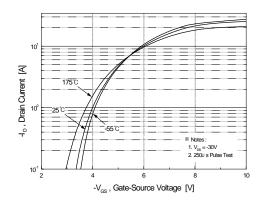


Figure 2. Transfer Characteristics

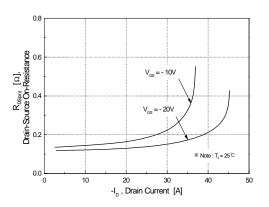


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

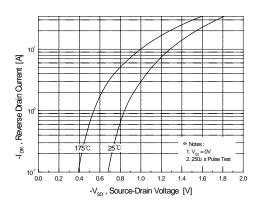


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

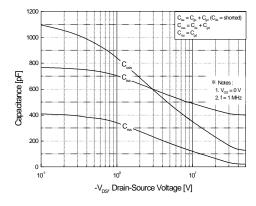


Figure 5. Capacitance Characteristics

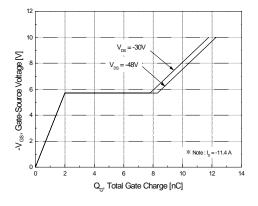
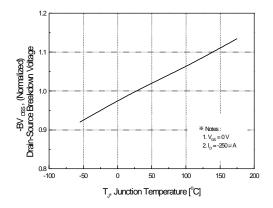


Figure 6. Gate Charge Characteristics

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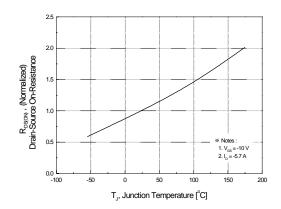
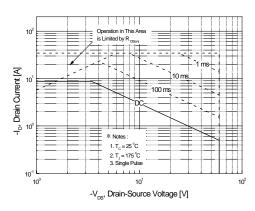


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



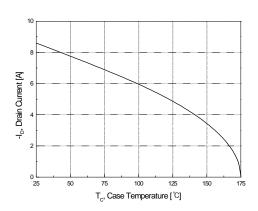


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

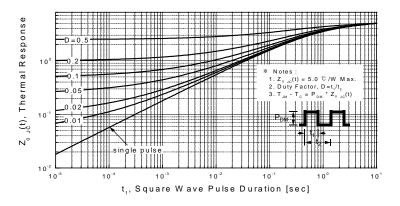
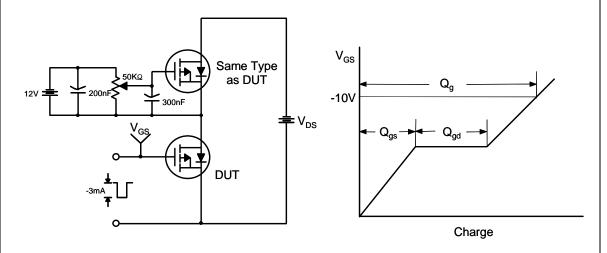


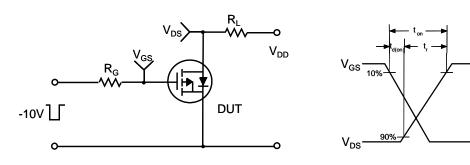
Figure 11. Transient Thermal Response Curve

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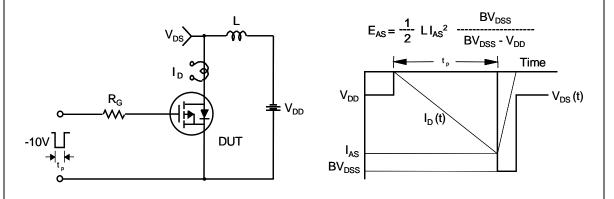
# **Gate Charge Test Circuit & Waveform**



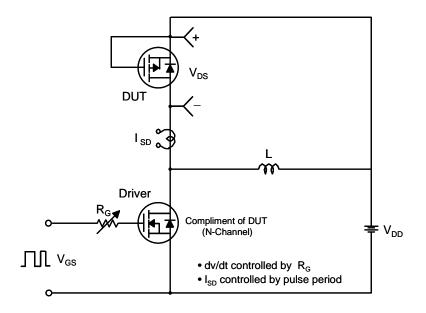
## **Resistive Switching Test Circuit & Waveforms**

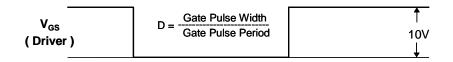


# **Unclamped Inductive Switching Test Circuit & Waveforms**

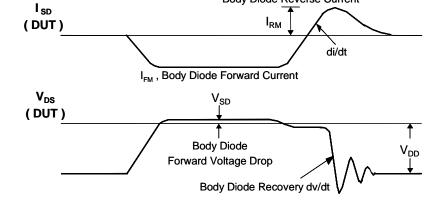


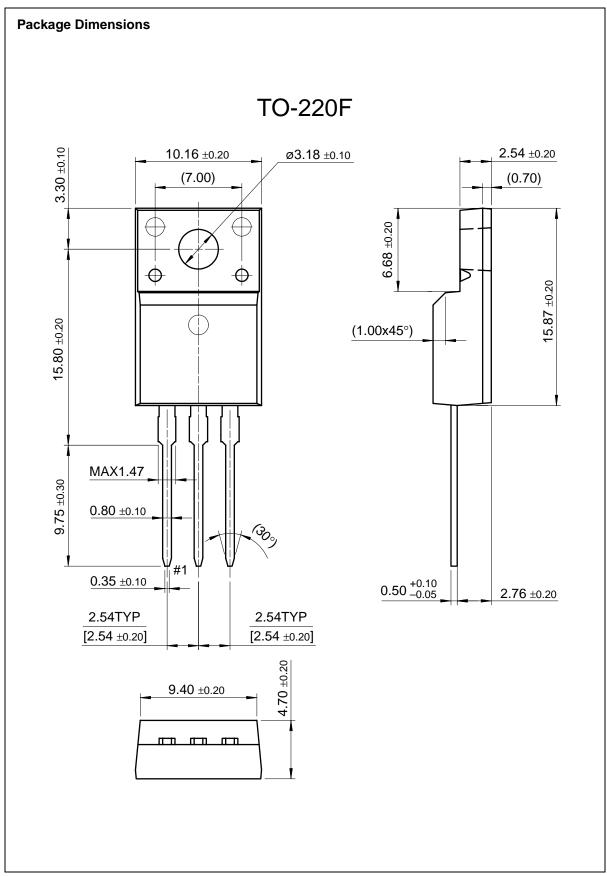
### Peak Diode Recovery dv/dt Test Circuit & Waveforms





**Body Diode Reverse Current** 





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